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The patents and/or publications submitted herewith are set forth on the attached Form PTO-1449.

If the sum of \$180.00 is due under 37 CFR § 1.17(p) pursuant to § 1.97, the Commissioner is hereby authorized to charge this fee, and any other fee necessary to make this submission timely, to the Deposit Account No. 20-0782/INFN/0056/GGM.

Respectfully submitted,



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Substitute for form 1449B/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  <i>(Use as many sheets as necessary)</i>		Application Number	Unknown		
		Filing Date	Herewith		
		First Named Inventor	MARIO DI RONZA		
		Group Art Unit	Unknown		
		Examiner Name	Unknown		
		Attorney Docket Number	INFN/0056		
Sheet	1	of	2	Submission Date	

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T <sup>2</sup>
	C1	TARR, ET AL., "Defect analysis system speeds Test and Repair of Redundant Memories," <i>M. Electronics</i> , January 12, 1984, pages 175-179, vol. 57, no. 1, VNU Business Publications, New York, U.S.A.	✓
	C2	GANAPATHY, ET AL., "Yield Modeling and Optimization of Large Redundant RAM's" <i>1990 International Conference on Wafer Scale Integration, WSI Design and Support Technology</i> , pages 273-287, IEEE Comput. Soc.	✓
	C3	DILIP K. BHAVSAR, "An Algorithm for Row-Column Self-Repair of RAMs and Its Implementation in the Alpha 21264" <i>ITC International Test Conference</i> , 1999, pages 311-318, <i>IEEE</i> .	✓
	C4	HEON-CHEOL KIM, "A BISR (Built-In Self-Repair) Circuit for Embedded Memory With Multiple Redundancies" <i>1999 IEEE</i> , pages 602-605.	✓
	C5	European Search Report for Application No. 03002698.3 dated October 1, 2003.	
	C6	Partial European Search Report for Application No. 03002698.3 dated July 23, 2003.	
	C7		
	C8		
	C9		
	C10		
	C11		
	C12		

Examiner	Date Considered
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Substitute for form 1449A/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  <i>(Use as many sheets as necessary)</i>				Application Number		Unknown	
				Filing Date		Her with	
				First Named Inventor		MARIO DI RONZA	
				Group Art Unit		Unknown	
				Examiner Name		Unknown	
				Attorney Docket Number		INFN/0056	
Sheet	1	of	2	Submission Date			

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
	A1	US- 5,808,945	09/15/1998	ARASE	
	A2	US- 6,026,505	02/15/2000	HEDBERG, ET AL.	
	A3	US- 2002/0108073	08/08/2002	HUGHES	
	A4	US- 6,141,267	10/31/2000	KIRIHATA, ET AL.	
	A5	US- 2002/159305	10/31/2002	YOO, ET AL.	
	A6	US-			
	A7	US-			
	A8	US-			
	A9	US-			
	A10	US-			
	A11	US-			
	A12	US-			
	A13	US-			
	A14	US-			
	A15	US-			
	A16	US-			
	A17	US-			
	A18	US-			

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Number-Kind Code <sup>2</sup> (if known)				
	B1					
	B2					
	B3					
	B4					
	B5					

Examiner	Date Considered
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This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO